

NanoLab Delivers!

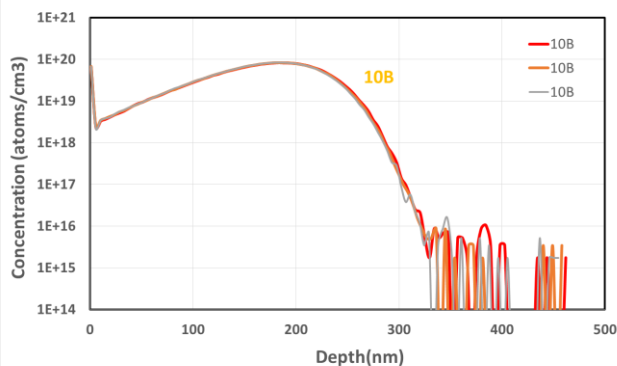
Fully upgraded Cameca ims 6f SIMS tool



With recent addition of two fully upgraded Cameca 6f IMS tools, Nanolab is now providing commercial SIMS services.

Secondary Ion Mass Spectrometry (SIMS) provides depth information of dopants and contaminants over a wide range of depth from a fraction of nanometers to tens of microns. The sample is sputtered by a primary ion such as Cs⁺ or O₂⁺. The secondary ions are extracted and analyzed using a mass spectrometer.

NIST 10B STD 2137: 1.02E+15 atoms/cm²



SIMS is a very sensitive technique with wide dynamic range capable to detect ions from ppb level to matrix levels.

Nanolab provides following SIMS Services:

- Dopant and impurity depth profiling
- Surface impurity analyses
- Thin film composition and impurity analyses
- Implant characterization and dose matching
- Advanced Sample Preparation
- Backside SIMS

Mg and Si doped GaN/AlGaN multilayer on Al₂O₃ substrate

